

Appendix C: System Calibration Certificate

Calibration information for E-field probes

Calibration Laboratory of

Schmid & Partner
Engineering AG

Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerischer Kalibrierdienst
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Accreditation No.: SCS 0108

Client

JYT

Shenzhen

Certificate No.

EX-3924_Oct25

CALIBRATION CERTIFICATE

Object

EX3DV4 - SN:3924

Calibration procedure(s)

QA CAL-01.v10, QA CAL-12.v10, QA CAL-14.v7, QA CAL-23.v6,
QA CAL-25.v8, QA CAL-48.v2
Calibration procedure for dosimetric E-field probes

Calibration date

October 08, 2025

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^\circ\text{C}$ and humidity $< 70\%$.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Calibration Date (Certificate No.)	Sched. Cal.
Power Sensor R&S NRP-33T	SN: 100967	30-Apr-25 (No. 1020-300791789)	Apr-26
N-type mismatch combination	SN: L1119	26-Mar-25 (No. 217-04292)	Mar-26
OCP DAK-12	SN: 1016	16-Sept-25 (No. OCP-DAK12-1016_Sep25)	Sep-26
OCP DAK-3.5	SN: 1249	16-Sept-25 (No. OCP-DAK3.5-1249_Sep25)	Sep-26
Reference Probe EX3DV4	SN: 7349	10-Jan-25 (No. EX3-7349_Jan25)	Jan-26
DAE4	SN: 1301	07-Nov-24 (No. DAE4-1301_Nov24)	Nov-25

Secondary Standards	ID	Check Date (in house)	Sched. Check
ACAP 2020 Setup 1	SN: L1404	01-Oct-25 (No. IHCK_ACAP2020-1_Oct25)	Oct-26
OCP DAK-12	SN: 1029	27-Feb-25 (No. OCP-DAK12-1029_Feb25)	Feb-26
OCP DAK-3.5	SN: 1336	09-Dec-24 (No. OCP-DAK3.5-1336_Dec24)	Dec-25

	Name	Function	Signature
Calibrated by	Jeton Kastrati	Laboratory Technician	
Approved by	Sven Kühn	Technical Manager	
Issued: October 09, 2025			
This calibration certificate shall not be reproduced except in full without written approval of the laboratory.			

Certificate No: EX-3924_Oct25

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Glossary

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C, D	modulation dependent linearization parameters
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis
Connector Angle	information used in DASY system to align probe sensor X to the robot coordinate system

Calibration is Performed According to the Following Standards:

- IEC/IEEE 62209-1528, "Measurement Procedure For The Assessment Of Specific Absorption Rate Of Human Exposure To Radio Frequency Fields From Hand-Held And Body-Worn Wireless Communication Devices – Part 1528: Human Models, Instrumentation And Procedures (Frequency Range of 4 MHz to 10 GHz)", October 2020.
- KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}**: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not affect the E²-field uncertainty inside TSL (see below ConvF).
- NORM(f)_{x,y,z} = NORM_{x,y,z} * frequency_response** (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal. DCP does not depend on frequency nor media.
- PAR**: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- A_{x,y,z}; B_{x,y,z}; C_{x,y,z}; D_{x,y,z}; VR_{x,y,z}**: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle**: The angle is assessed using the information gained by determining the NORM_x (no uncertainty required).

Parameters of Probe: EX3DV4 - SN:3924

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k = 2)
Norm ($\mu V/(V/m)^2$) ^A	0.63	0.57	0.65	±10.1%
DCP (mV) ^B	107.5	108.5	107.1	±4.7%

Calibration Results for Modulation Response

UID	Communication System Name		A dB	B dB $\sqrt{\mu V}$	C	D dB	VR mV	Max dev.	Max Unc ^E k = 2
0	CW	X	0.00	0.00	1.00	0.00	126.6	±1.6%	±4.7%
		Y	0.00	0.00	1.00		142.3		
		Z	0.00	0.00	1.00		128.1		

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of Norm X,Y,Z do not affect the E²-field uncertainty inside TSL (see Page 5).
^B Linearization parameter uncertainty for maximum specified field strength.
^E Uncertainty is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

Parameters of Probe: EX3DV4 - SN:3924**Other Probe Parameters**

Sensor Arrangement	Triangular
Connector Angle	29.2°
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	12 mm
Tip Length	9 mm
Tip Diameter	2.5 mm
Probe Tip to Sensor X Calibration Point	1 mm
Probe Tip to Sensor Y Calibration Point	1 mm
Probe Tip to Sensor Z Calibration Point	1 mm
Recommended Measurement Distance from Surface	1.4 mm

Note: Measurement distance from surface can be increased to 3–4 mm for an *Area Scan* job.

Parameters of Probe: EX3DV4 - SN:3924**Calibration Parameter Determined in HSL**

f (MHz) ^C	Relative Permittivity ^F	Conductivity ^F (S/m)	ConvF X	ConvF Y	ConvF Z	Alpha ^G	Depth ^G (mm)	Unc ^H (k = 2)
750	41.9	0.89	10.00	9.39	9.50	0.35	1.27	±11.0%
835	41.5	0.90	9.80	9.21	9.31	0.35	1.27	±11.0%
1750	40.1	1.37	8.34	7.83	7.92	0.34	1.27	±11.0%
1900	40.0	1.40	7.88	7.40	7.49	0.33	1.27	±11.0%
2450	39.2	1.80	7.30	6.86	6.94	0.33	1.27	±11.0%
2600	39.0	1.96	7.20	6.77	6.85	0.33	1.27	±11.0%
5250	35.9	4.71	5.48	5.15	5.21	0.29	1.27	±13.1%
5600	35.5	5.07	5.06	4.76	4.81	0.27	1.27	±13.1%
5750	35.4	5.22	5.10	4.79	4.85	0.26	1.27	±13.1%

^C Frequency validity above 300 MHz of ±100 MHz only applies for DASY v4.4 and higher (see Page 2), else it is restricted to ±50 MHz. The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band. Frequency validity below 300 MHz is ±10, 25, 40, 50 and 70 MHz for ConvF assessments at 30, 64, 128, 150 and 220 MHz respectively. Validity of ConvF assessed at 6 MHz is 4–9 MHz, and ConvF assessed at 13 MHz is 9–19 MHz. Above 5 GHz frequency validity can be extended to ±110 MHz.

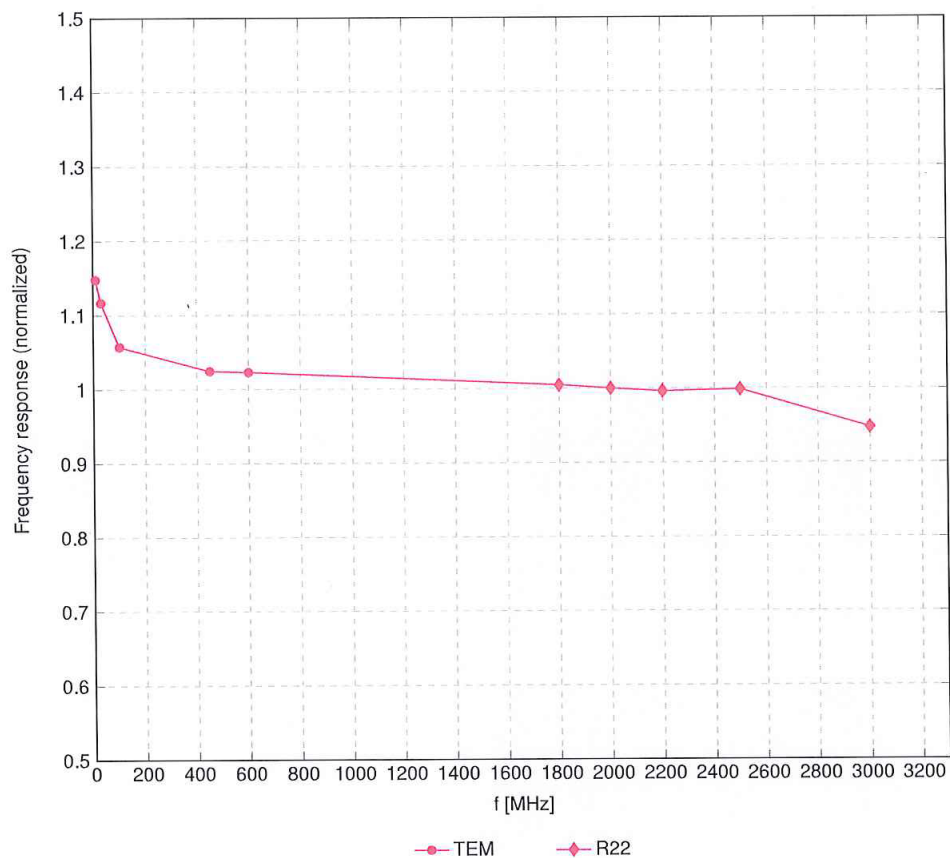
^F The probes are calibrated using tissue simulating liquids (TSL) that deviate for ϵ and σ by less than ±5% from the target values (typically better than ±3%) and are valid for TSL with deviations of up to ±10% if SAR correction is applied.

^G Alpha/Depth are determined during calibration. SPEAG warrants that the remaining deviation due to the boundary effect after compensation is always less than ±1% for frequencies below 3 GHz and below ±2% for frequencies between 3–6 GHz at any distance larger than half the probe tip diameter from the boundary.

^H The stated uncertainty is the total calibration uncertainty (k = 2) of Norm-ConvF. This is equivalent to the uncertainty component with the symbol CF in Table 9 of IEC/IEEE 62209-1528:2020.

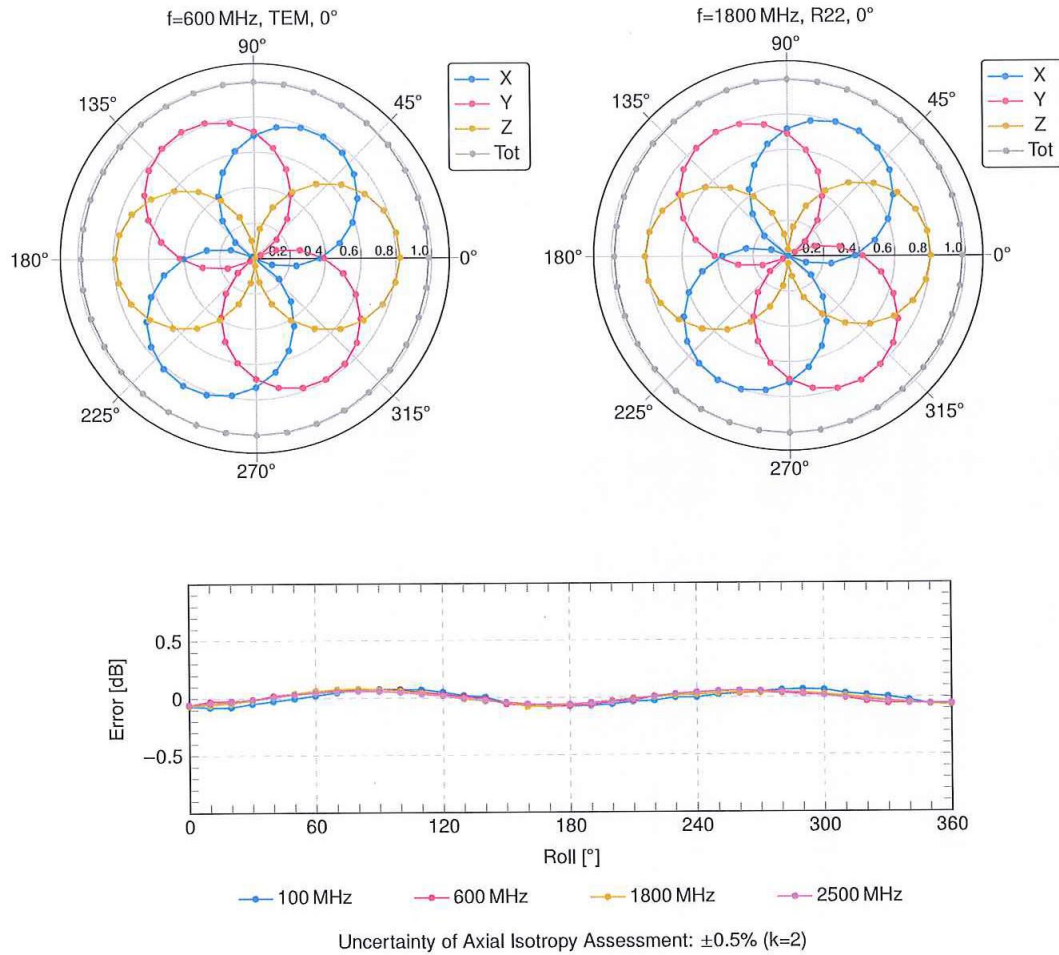
Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide:R22)



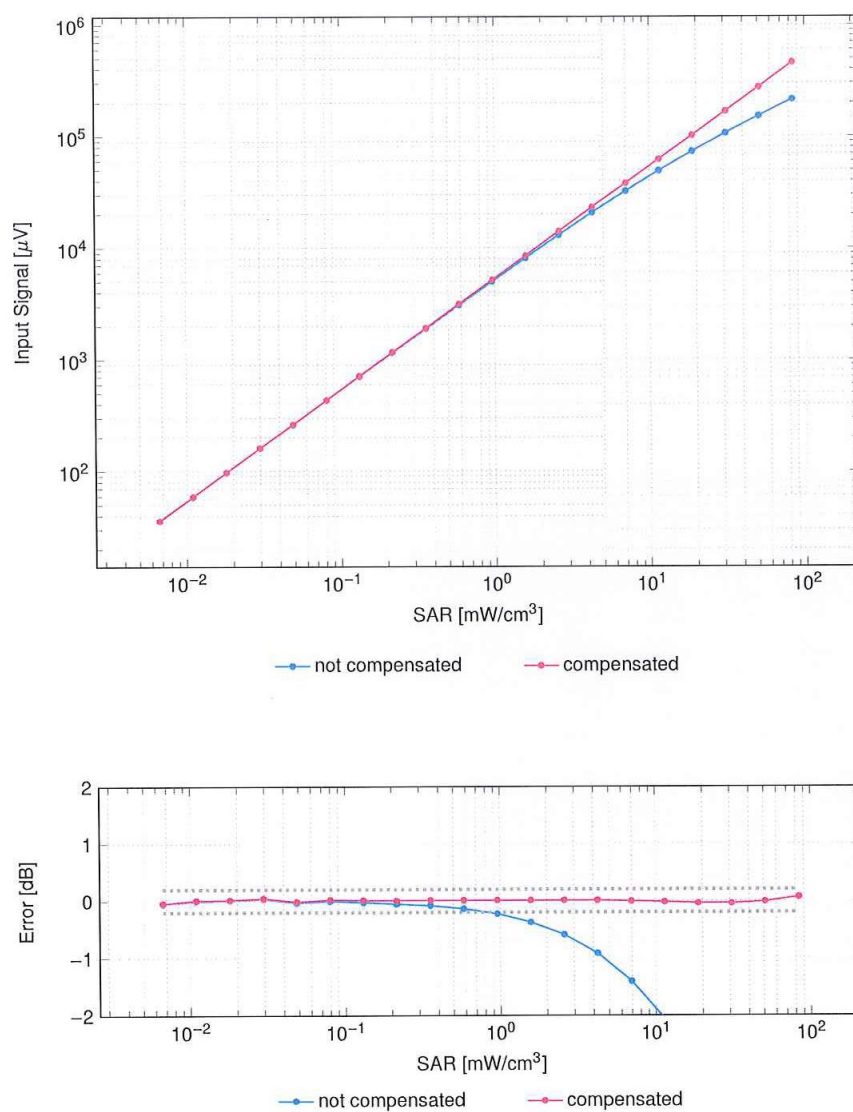
Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)

Receiving Pattern (ϕ), $\theta = 0^\circ$



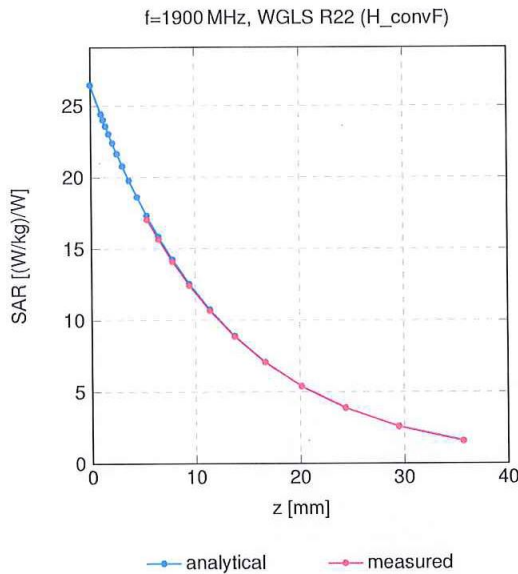
Dynamic Range $f(\text{SAR}_{\text{HSL}})$

(TEM cell, $f_{\text{eval}} = 1900\text{MHz}$)

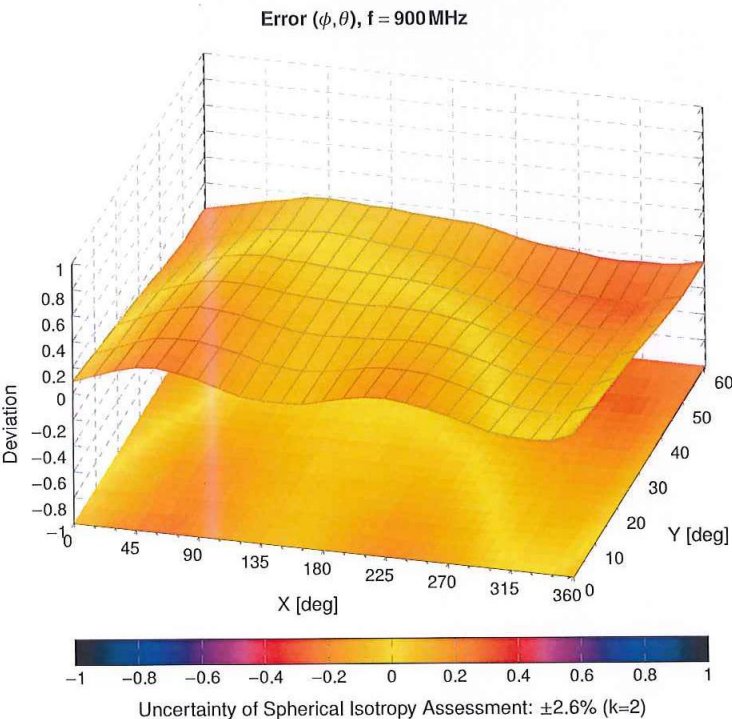


Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)

Conversion Factor Assessment



Deviation from Isotropy in Liquid



Calibration information for Dipole



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CNAS L0570



Client **JYT(Shenzhen)**

Certificate No: **25J02Z000314**

CALIBRATION CERTIFICATE

Object **D2450V2 - SN: 910**

Calibration Procedure(s) **FF-Z11-003-01**
Calibration Procedures for dipole validation kits

Calibration date: **May 9, 2025**

This calibration Certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22±3)°C and humidity<70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
Power Meter NRP2	101919	12-Jun-24 (CTTL, No.24J02X005418)	Jun-25
Power sensor NRP-Z91	101547	12-Jun-24 (CTTL, No.24J02X005418)	Jun-25
Reference Probe EX3DV4	SN 3846	19-Jun-24(CTTL-SPEAG, No. 24J02Z000266)	Jun-25
DAE4	SN 1588	13-Sep-24(CTTL-SPEAG, No. 24J02Z000713)	Sep-25
Secondary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
Signal Generator E4438C	MY49071430	19-Dec-24 (CTTL, No. 24J02X103931)	Dec-25
NetworkAnalyzer E5071C	MY46110673	18-Dec-24 (CTTL, No. 24J02X103932)	Dec-25
OCP DAKS	SN 0015	09-Oct-24(SPEAG, No. OCP-DAKS-0015_Oct24)	Oct -25

	Name	Function	Signature
Calibrated by:	Zhao Jing	SAR Test Engineer	
Reviewed by:	Lin Jun	SAR Test Engineer	
Approved by:	Qi Dianyuan	SAR Project Leader	

Issued: May 21, 2025

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Certificate No: 25J02Z000314

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